

Search Notes

Application/Control No.

10/820,722

Examiner

James D. Ewart

Applicant(s)/Patent under
Reexamination

LIAO ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	405 406 414.1 414.2 414.3	10/23/2006	JDE
	426.1 466		
701	200 201		
	208-211		
370	395.5		
707	104.1		
709	217-219		
	230		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR